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| Notice of References Cited | Application/Control No. 10/807,659 | Applicant(s)/Patent Under Reexamination GOO ET AL. | |
| | Examiner Kevin Gutierrez | Art Unit 2851 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-6,052,173 A | 04-2000 | Miura et al. | 355/53 |
| * | B | US-4,905,037 | 02-1990 | Yamamoto et al. | 355/402 |
| * | C | US-5,811,211 A | 09-1998 | Tanaka et al. | 430/30 |
| * | D | US-5,381,429 A | 01-1995 | Minemoto et al. | 372/21 |
| * | E | US-6,577,436 B2 | 06-2003 | Kim, Jong-Ryeol | 359/332 |
| * | F | US-4,899,195 | 02-1990 | Gotoh, Manabu | 355/77 |
| * | G | US-2002/0092964 A1 | 07-2002 | Kim, Jeong Yeal | 250/201.2 |
| * | H | US-5,204,224 A | 04-1993 | Suzuki, Shinji | 430/315 |
| * | I | US-2003/0117597 A1 | 06-2003 | Sato et al. | 355/53 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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